


<b>Search Notes</b>  	<b>Application/Control No.</b>  10590899	<b>Applicant(s)/Patent Under Reexamination</b>  FUKUMATSU ET AL.
	<b>Examiner</b>  Dawn Garrett	<b>Art Unit</b>  1794

SEARCHED			
Class	Subclass	Date	Examiner
	(see EAST search history printout for details)	3/16/2009	DG

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor Name Search	3/16/2009	DG
EAST search (see search history printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	3/16/2009	DG
EIC 1700 STIC structure search (see attached printout)	3/10/2009	DG
updated EAST search (see search history printout attached); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	8/28/2009	DG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--